Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/765,118	LEE ET AL.
Examiner	Art Unit
J. Pasterczyk	1755

SEARCHED					
Class	Subclass	Date	Examiner		
502	158	5/06	AP		
,	159				
	172				
	239				
	242				
	239 242 350				
923	610				
	}				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Soz	158,159	5/06	SP		
	172,239	•			
	242, 350				
923	610				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMF		
Inventor search	5/06	AP		